Application/Control No. Applicant(s)/Patent Under Reexamination 10/643,858 CHAN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1755 J. Pasterczyk **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,825,296 11-2004 Chi-Wang Chan et al. 526/161 Α US-2003/0191015 A 10-2003 Chi-Wang Chan et al. 502/150 В US-С US-D US-Ε US-F UŞ-G

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